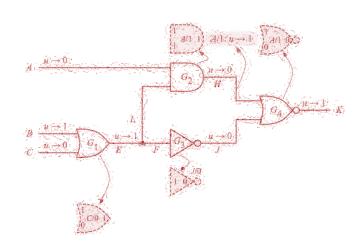
Fault Simulation

- Introduction
- Fault simulation techniques
 - Serial fault simulation
 - Parallel fault simulation (1965)
 - PPSFP (1985)
 - Deductive fault simulation (1972)
 - Concurrent fault simulation (1974)
 - Differential fault simulation (1989)
- Alternatives to fault simulation
- Issues of fault simulation
- Concluding remarks

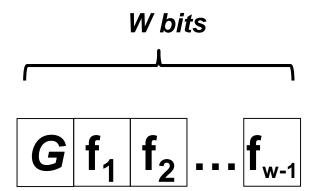


Two Types of Parallelism

- Exploit parallelism of logic instructions (bit-wise operations)
 - 1. Parallelism in faults
 - Parallel Fault Simulation [Seshu 65]
 - 2. Parallelism in patterns
 - Parallel Pattern Single Fault Propagation, PPSFP [Wacukauski 85]

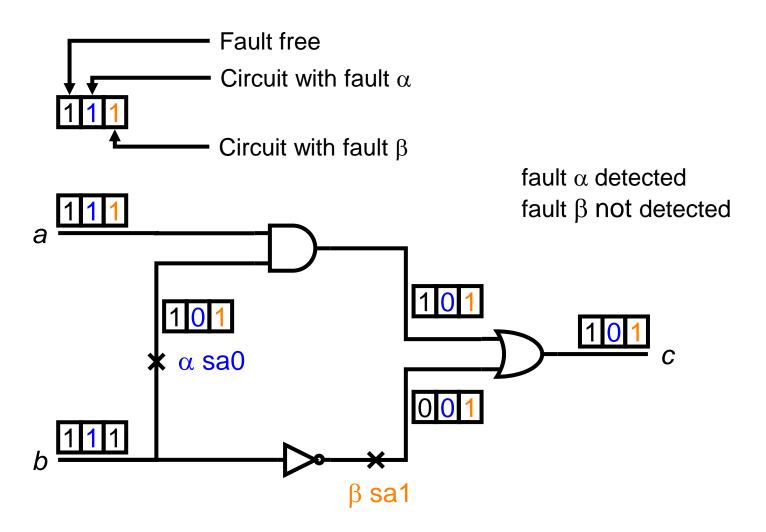
Parallel Fault Simulation [Seshu 65]

- Run parallel logic simulation with W-1 faults (W is CPU word size)
 - one bit for fault-free circuit
 - W-1 bits for faulty circuit
- (W-1) times faster than serial fault simulation (w/o fault dropping)



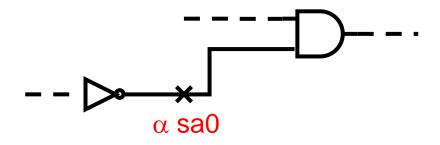
Example

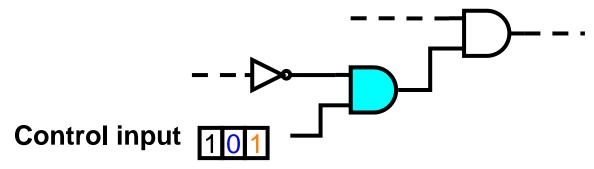
• Assume W=3



Fault Injection

Fault Injection = inserting fault(s) into circuit





0 = SA0 fault injected

1 = SA0 fault not injected

Quiz: how to insert SA1 fault?

A:

Quiz

010 -

Q: Consider two faults: (f=SA1, g=SA0). Use parallel fault simulation on patterns

 $P_1 = \{010\},\ P_2 = \{001\},\ P_3 = \{100\}.$

A:

010 110 -010 - G_4 110 -

Assume no fault dropping

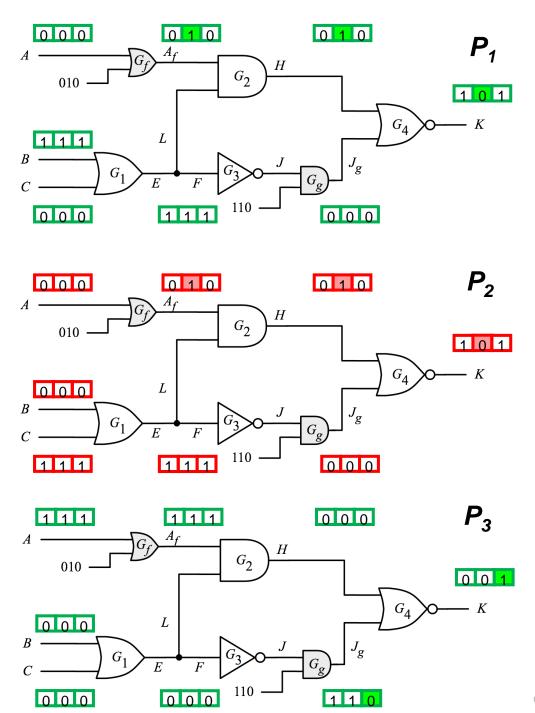
Solution

Q: Consider two faults: (f=SA1, g=SA0). Use parallel fault simulation on patterns

 $P_1 = \{010\},\ P_2 = \{001\},\ P_3 = \{100\}.$

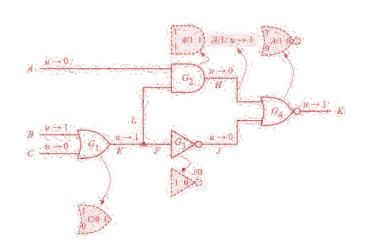
A: $P_1 P_2$ detect f P_3 detects g

Assume no fault dropping



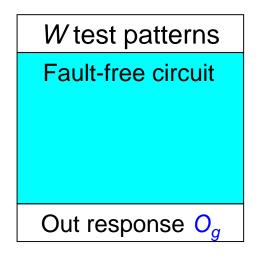
Fault Simulation

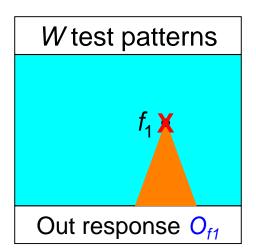
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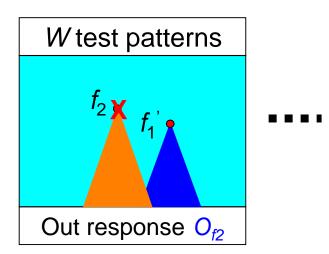


PPSFP

- Parallel pattern assumes combinational circuit
- Procedure
 - Step 0: run logic simulation, store good output Og
 - Step 1: Inject f₁ by creating an event at the fault site
 - Step 2: Perform event-driven simulation, get output Off
 - * Compare O_g and O_{f1}
 - Step 3. Create an event to undo fault effect of f₁
 - Inject an event for next fault f₂
 - Repeat step 2~3 until all faults simulated

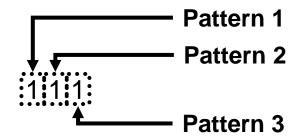


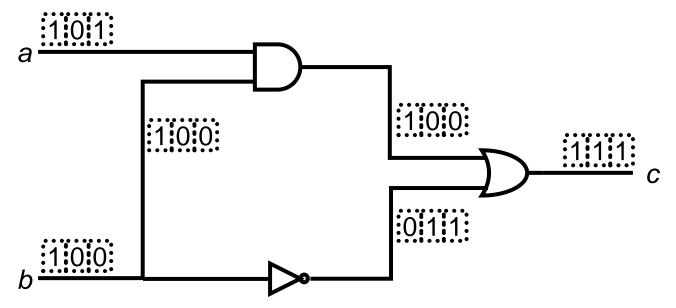




PPSFP Example

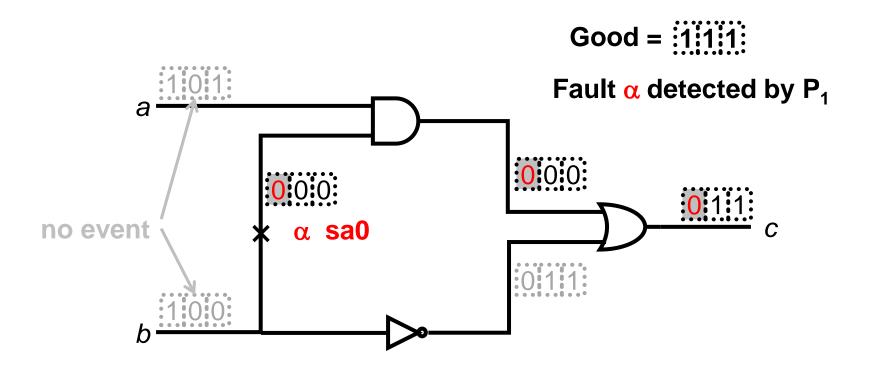
- Assume W=3
- Fault-free circuit
 - Fault-free output 111 stored





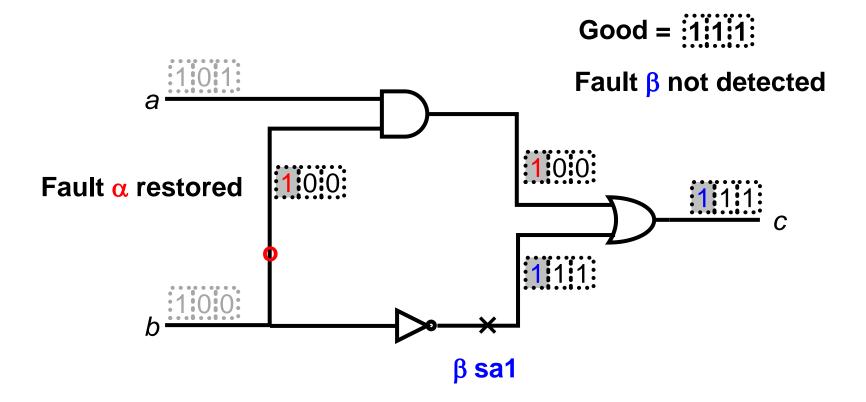
Example-cont'd

- One event created to inject fault α
 - fault effects are then propagated



Example – cont'd

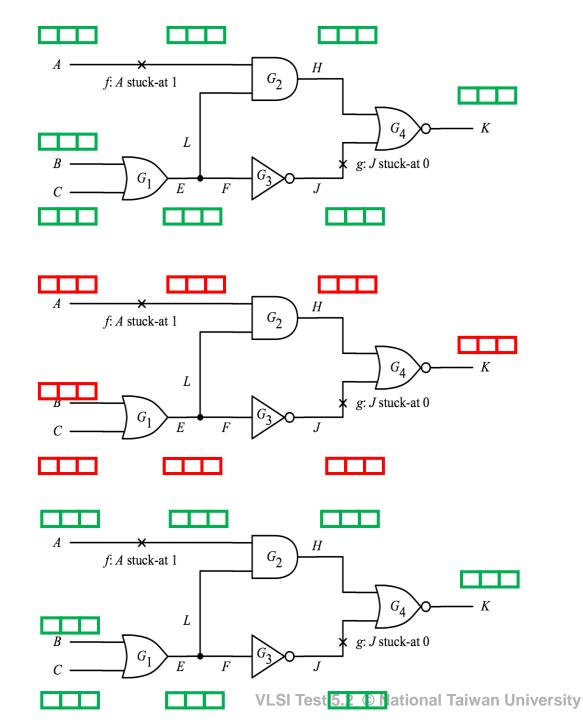
- Two events created:
 - One event to restore fault a
 - One event to inject fault β



Quiz

Q: Consider two faults: (f=SA1, g=SA0). Use PPSFP on patterns $P_1=\{010\}, P_2=\{001\}, P_3=\{100\}.$

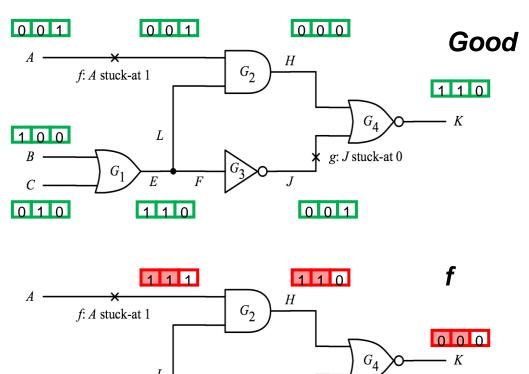
A:

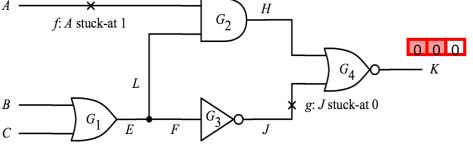


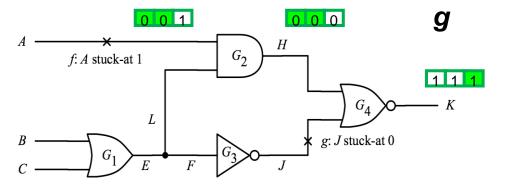
Solution

Q: Consider two faults: (f=SA1, g=SA0). Use **PPSFP** on patterns $P_1 = \{010\},$ $P_2 = \{001\},$ $P_3 = \{100\}.$

A: $P_1 P_2$ detect f P_3 detects g





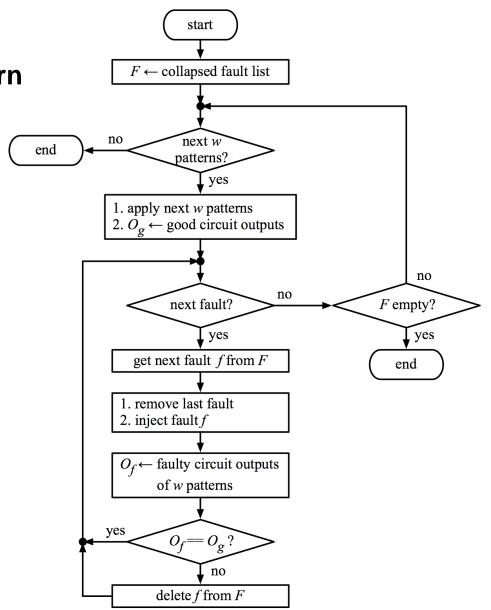


PPSFP Flow Chart

inner loop: fault

outer loop: pattern

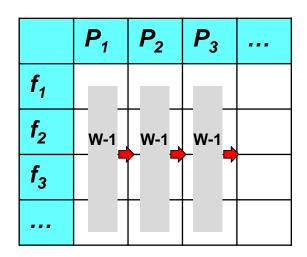
• (WWW Fig 3.25)

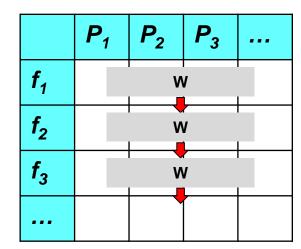


Comparison

- Serial fault simulation: one fault, one pattern
- Parallel fault simulation: multiple faults, one pattern
- PPSFP: multiples pattern, one fault

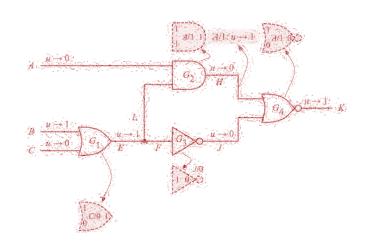
	P ₁	P ₂	P ₃	
f ₁	=	†	•	
f ₂	4		•	
f ₃	4		•	,
	4			





Summary

- Parallel fault simulation (parallel in fault)
 - Run parallel logic simulation for W-1 faults
 - Fault injection by circuit modification
- Parallel Pattern Single fault Propagation (parallel in pattern)
 - Run parallel logic simulation for W patterns



FFT

Q1: Why parallel fault sim (W-1) faults, not W faults?

Q2: Please compare parallel fault sim and PPSFP

Q3: PPSFP is useful to comb. ckt only, how about sequential ckt?

	Parallel Fault	PPSFP
Applicable to delay fault model?		
Applicable to Sequential ckt ?		
When to drop fault?		